

# FDC655BN Single N-Channel, Logic Level, PowerTrench® MOSFET

### **Features**

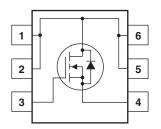
- 6.3 A, 30 V.  $R_{DS(ON)} = 25 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 33 \text{ m}\Omega$  @  $V_{GS} = 4.5 \text{ V}$
- Fast switching
- Low gate charge
- High performance trench technology for extremely low Rdson

### **General Description**

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimized on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.





### Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage		30	V	
V <sub>GSS</sub>	Gate-Source Voltage		±20	V	
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	6.3	А	
	– Pulsed		20		
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	1.6	W	
		(Note 1b)	0.8		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		- 55 to +150	°C	
Thermal Characteristics					
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	30	°C/W	

# **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape width	Quantity
.55B	FDC655BN	7"	8mm	3000 units

## **Electrical Characteristics** $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Characte	eristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		23		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = -55°C			1 10	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Characte	eristics (Note 2)				•	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		- 4.1		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}, T_J = 125 ^{\circ}\text{C}$		20 26 27	25 33 45	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 6.3 A		20		S
Dynamic Ch	aracteristics		'			
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V,		570		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		140		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			70		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		2.1		Ω
Switching C	characteristics (Note 2)		'			
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A,		8	16	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		4	8	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			22	35	ns
t <sub>f</sub>	Turn-Off Fall Time			3	6	ns
Q <sub>g(TOT)</sub>	Total Gate Charge at Vgs=10V	$V_{DD} = 15 \text{ V}, I_D = 6.3 \text{ A},$		10	15	nC
Q <sub>g(TOT)</sub>	Total Gate Charge at Vgs=5V			6	8	nC
Q <sub>gs</sub>	Gate-Source Charge			1.7		nC
Q <sub>gd</sub>	Gate-Drain Charge			2.1		nC
	ce Diode Characteristics and Maximu	m Ratings	-			
I <sub>S</sub>	Maximum Continuous Drain-Source D	ce Diode Forward Current		1.3	Α	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.3 A (Note 2)		0.8	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 6.3 \text{ A}, d_{IF}/d_t = 100 \text{ A}/\mu\text{s}$ 18			ns	
Q <sub>rr</sub>	Diode Reverse Recovery Charge			9		nC

### Notes:

R<sub>BJA</sub> is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.

a.  $78^{\circ}\text{C/W}$  when mounted on a  $1\text{in}^2$  pad of 2oz copper on FR-4 board.

b. 156°C/W when mounted on a minimum pad.

<sup>2.</sup> Pulse Test: Pulse Width  $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$ 

### **Typical Characteristics**

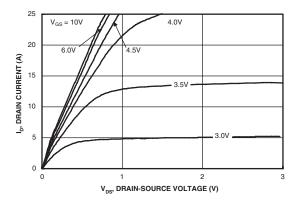


Figure 1. On-Region Characteristics.

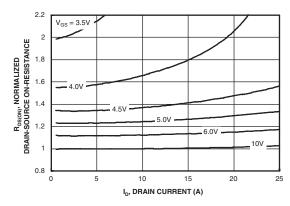


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

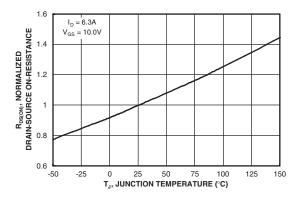


Figure 3. On-Resistance Variation withTemperature.

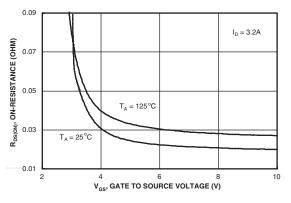


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

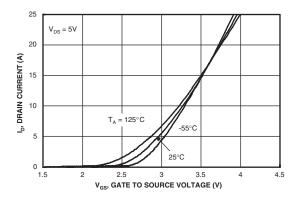


Figure 5. Transfer Characteristics.

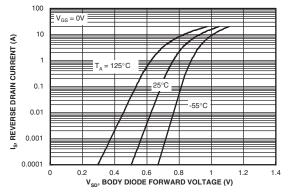


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**

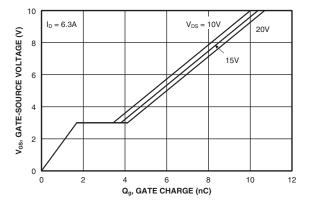
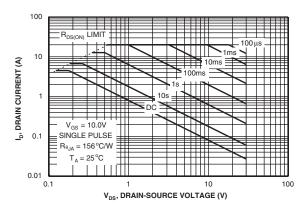


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



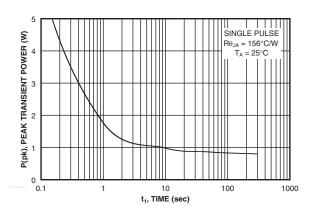


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

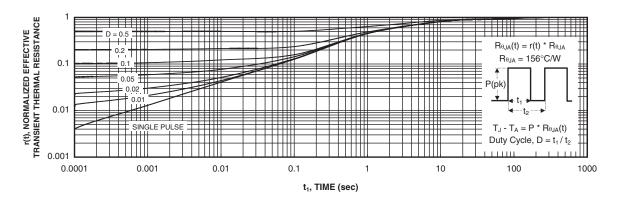


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

4

### **Typical Characteristics**

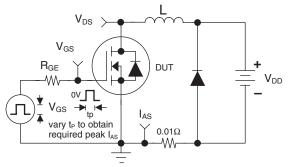


Figure 12. Unclamped Inductive Load Test Circuit

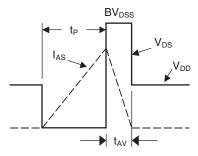


Figure 13. Unclamped Inductive Waveforms

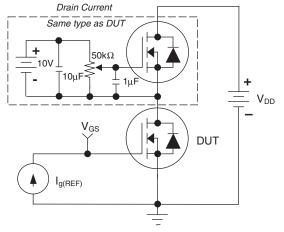


Figure 14. Gate Charge Test Circuit

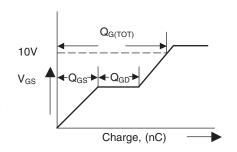


Figure 15. Gate Charge Waveform

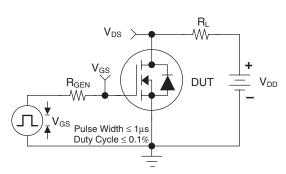


Figure 16. Switching Time Test Circuit

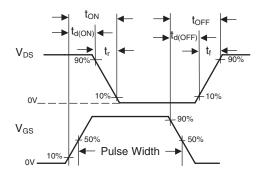


Figure 17. Switching Time Waveforms

#### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FAST®	IntelliMAX™	РОР™	SPM™
ActiveArray™	FASTr™	ISOPLANAR™	Power247™	Stealth™
Bottomless™	FPS™	LittleFET™	PowerEdge™	SuperFET™
CoolFET™	FRFET™	MICROCOUPLER™	PowerSaver™	SuperSOT™-3
CROSSVOLT™	GlobalOptoisolator™	MicroFET™	PowerTrench®	SuperSOT™-6
DOME™	GTO™ .	MicroPak™	QFET®	SuperSOT™-8
EcoSPARK™	HiSeC™	MICROWIRE™	QS <sup>TM</sup>	SyncFET™
E <sup>2</sup> CMOS <sup>TM</sup>	I <sup>2</sup> C <sup>TM</sup>	MSX™	QT Optoelectronics™	TinyLogic <sup>®</sup>
EnSigna™	<i>i-Lo</i> ™	MSXPro™	Quiet Series™	TINYOPTO™
FACT™	ImpliedDisconnect™	$OCX^{TM}$	RapidConfigure™	TruTranslation™
FACT Quiet Series™		OCXPro <sup>™</sup>	RapidConnect™	UHC™
Across the board. Around the world.™ The Power Franchise® Programmable Active Droop™		OPTOLOGIC <sup>®</sup> OPTOPLANAR™ PACMAN™	µSerDes™ SILENT SWITCHER® SMART START™	UltraFET® UniFET™ VCX™

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

### **PRODUCT STATUS DEFINITIONS**

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

6

Rev. I15